PLUS

	L#	Hits	Search T xt	DBs	Tim Stamp	Туре
1	L1	50	("4294404" "5778075" "5794147" "5870673" "6285881" "6792323" "4761641" "5826117" "5850577" "5305037" "5504935" "4509842" "5371566" "6144312" "4403285" "4425531" "4793980" "4805112" "4827410" "4835679" "4918379" "4971796" "5177524" "5267085" "5339126" "5392159" "5392502" "5442779" "5522028" "5568545" "5663954" "5692223" "5740070" "5844805" "5966550" "5986586" "6021514" "6034723" "6041515" "6209034" "6241456" "6247028" "6339670" "6407417" "6409198" "6457654" "4281775" "4246776" "4261132" "4335376").pn.	IDSPAT	2004/12/12 10:03	BRS

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Most Frequently Occurring Classifications of Patents Returned From A Search of 10749698 on November 26, 2004

Original Classifications

2 455/434

Cross-Reference Classifications

- 3 455/552.1
- 2 345/179
- 2 359/705
- 2 359/823
- 2 375/216
- 2 396/89
- 2 455/454
- 2 455/67.11

Combined Classifications

- 3 455/434
- 3 455/552.1
- 2 345/179
- 2 359/694
- 2 359/705
- 2 359/823
- 2 375/216
- 2 396/103
- 2 396/79
- 2 396/82
- 2 396/85
- 2 396/89
- 2 455/454
- 2 455/67.11
- 2 700/180

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	L1!4_	Search Tout	DD-	Tim 04	T
L#	HITS	Search Text		iim Stamp	туре
L1	67305	process ADJ control	EPO; JPO; DERWENT; IBM_TDB	2004/12/12 10:21	BRS
L2	426	L1 SAME recipe	EPO; JPO; DERWENT; IBM_TDB	2004/12/12 10:21	BRS
L3	116	L2 SAME (prior OR past OR feedback OR feed ADJ back OR histor\$ OR previous\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/12/12 10:25	BRS
L4	569	RBR OR "run-by -run"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/12/12 12:28	BRS
L5	1	L3 AND L4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/12/12 10:25	BRS
L6	73	L4 SAME (prior OR past OR feedback OR feed ADJ back OR histor\$ OR previous\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/12/12 10:26	BRS
L7	115	L3 NOT (L5 OR L6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/12/12 10:26	BRS
L8	12	("6249712").URPN.	USPAT	2004/12/12 11:35	BRS
L10	296	L4 NOT (L5 OR L6 OR L7 OR L8)	USPAT	2004/12/12 12:28	BRS
L11	10	("6587744").URPN.	USPAT	2004/12/12 11:53	BRS
L12	41	("5926690").URPN.	USPAT	2004/12/12 12:05	BRS
L13	0	("6625513").URPN.	USPAT	2004/12/12 12:08	BRS
L14	686	"run-by-run" OR "run-to-run"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/12/12 12:28	BRS
L15	424	L14 NOT (L5 OR L6 OR L7 OR L8 OR L10 OR L11 OR L12)	USPAT	12:29	BRS
L16	160	L15 AND (L1 OR recipe)	USPAT	2004/12/12 12:29	BRS
	L2 L3 L4 L5 L6 L7 L8 L10 L11 L12 L13 L14	L1 67305 L2 426 L3 116 L4 569 L5 1 L6 73 L7 115 L8 12 L10 296	L1 67305 process ADJ control L2 426 L1 SAME recipe L3 116 L2 SAME (prior OR past OR feedback OR feed ADJ back OR histor\$ OR previous\$3) L4 569 RBR OR "run-by -run" L5 1 L3 AND L4 L6 73 L4 SAME (prior OR past OR feedback OR feed ADJ back OR histor\$ OR previous\$3) L7 115 L3 NOT (L5 OR L6) L8 12 ("6249712").URPN. L10 296 L4 NOT (L5 OR L6 OR L7 OR L8) L11 10 ("6587744").URPN. L12 41 ("5926690").URPN. L13 0 ("6625513").URPN. L14 686 "run-by-run" OR "run-to-run" L15 424 L14 NOT (L5 OR L6 OR L7 OR L8 OR L10 OR L11 OR L12)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	US-PGPUB, USPAT; 10:21 10:25 1

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_	Decument ID	US-PG	***************************************	T##e MULTIVARIATE RBR TOOL	Current	inventor Sun, Cheng-let			images6 US	90.D P	=
₽.	20040110310 41	PUB		AGING DETECTOR		al.	n s	ים א	2004011	i	
ß	US 6249712 B1	USPAT	20010619	Adaptive control process and system	700/31	Boiquaye; William J. N-O.	n r	n n	US 6249	712 []	
г	US 6408220 B1	USPAT	20020618	Semiconductor processing techniques	700/121	Nulman; Jaim	₽ r	r	US 6408	220	
P.	US 6796883 B1	USPAT	20040928	Controlled lubricated finishing	451/41	Molnar, Charles	гr	7 (7)	US 8798	883	
		USPAT	20040601	Method and apparatus for	700/28	Pasadyn; Alexander J. et	5 F	, بسر ب	US 6745	086	
	US 6719615	USPAT	20040413	determining control actions incorporation, defectivity, effect Versatile wafer refining	451/41	Molnar, Charles			US 6719	615	
	B1 US 6587744	USPAT	20030701	Run-to-run controller for use		J. Stoddard; Kevir			 US 6507	744 T.	
P.	B1			in microelectronic fabrication		D. et al.	cr			С	
	US 6773931 B2	USPAT	20040810	Dynamic targeting for a process control system	438/10	Pasadyn; Alexander J. et	P. I	r	_; US 6773	931	
Γ.	US 6751518 B1	USPAT	20040815	Dynamic process state adjustment of a processing	700/121	Sonderman; Thomas J. et al	P. C		US 6751	518	
8	US 6701206 B1	USPAT	20040302	thou to reduce con-uniformity Method and system for controlling a process tool	700/121	Markle; Richard J. et al.	n n	. c. í	US 6701	206 1.7	
	US 6698009 B1	USPAT	20040224	Method and apparatus for modeling of batch dynamics	716/19	Pasadyn; Alexander J. et	рr		US 6698	009	
	US 6427093	USPAT	20020730	hased upon integrated metrol Method and apparatus for	700/121	Toprac;		rı	US 6427	093	
	B1 US 6419801	USPAT	20020716	optimal wafer-by-wafer concession Method and apparatus for	204/192	Anthony J. Smith, Jr.;	ļļ		116 6410	801	
	B1 US 8383402	LISPAT	20020507	monitoring plasma processing operations Method and apparatus for	13 216/60	Michael Lane et al.	K L	r n		n	
r	B1			monitoring plasma		Smith, Jr.; Michael Lane et	R C	; C (US 8383	402 C	
	US 6275740 B1	USPAT	20010814	Method and apparatus for monitoring plasma	700/108	Smith, Jr.; Michael Lane et	F ſ	c	US 6275	740 C	
	US 6269278 B1	USPAT	20010731	ntoressing operations Method and apparatus for monitoring plasma	700/121	Smith, Jr.; Michael Lane et	PI	េក	US 6269	278 C	
	US 6261470 B1	USPAT	20010717	nrocessing operations Method and apparatus for monitoring plasma	216/60	Smith, Jr.; Michael Lane et	Pr	rı	US 6261	470	
	US 6254717 B1	USPAT	20010703	processing operations. Method and apparatus for	156/345	al. Smith, Jr.; Michael Lane et			US 8254	717	
	US 6246473	USPAT	20010612	monitoring plasma processing operations Method and apparatus for	24 356/316	.lal	ļļ		110 0040	473	
	B1 US 6223755	USPAT	20010501	monitoring plasma procession operations Method and apparatus for	134/1.1	Michael Lane et	 		US 6223	∏. 755	
	B1 US 6221679	LICOAT	20010424	monitoring plasma		Michael Lane et	P. I.	ci		n	
г 	B1			Method and apparatus for monitoring plasma arccession operations	438/7	Smith, Jr.; Michael Lane et	P l	r	US 6221	ь/ 9	
Γ	US 6192826 B1	USPAT	20010227	Method and apparatus for	118/723 AN	Smith, Jr.; Michael Lane et	P7 [r r	US 6192	826 F:	
r	US 6169933 B1	USPAT	20010102	Method and apparatus for monitoring plasma	700/121	Smith, Jr.; Michael Lane et	ξ.	េក	US 6169	933	
···	US 6165312 A	USPAT	20001228	nrocessing operations Method and apparatus for monitoring plasma	156/345. 24	Smith, Jr.; Michael Lane et	·		119 8185	312	
 _	US B157447 A	USPAT	20001205	procession operations Method and apparatus for monitoring plasma	356/318	al Smith, Jr.; Michael Lane et	ļļ		US 8157	447	
_	US 6134005 A	USPAT	20001017	nrocession operations Method and apparatus for	356/451	al		<u></u>	116 6124	005	
	US 6132577 A	USPAT	20001017	monitoring plasma procession operations Method and apparatus for	: 	Michael Lane et al Smith, Jr.;	 	-}}-		577	
	US 6123983 A			monitoring plasma nrncession onerations	32	Michael Lane et	R L	C	7	Г	
Γ.				monitoring plasma	427/10	Smith, Jr.; Michael Lane et al	Б . С	C t		n	
	US 6090302 A		20000718	Method and apparatus for monitoring plasma	216/60	Smith, Jr.; Michael Lane et	P [רנ	US 6090:	302 [:]	*
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EAST - [10749698.wsp:1] View Eda Teals Window Help // *** 1** A BRS torm A ISSR torm 1 Decument ID Source Issue Date Mage Ooc C P Title Current inventor US 6698009 USPAT 20040224 Method and apparatus for 716/19 US 6698009 :Pasadyn; RCCC modeling of batch dynamics Alexander J. et hased unon interrated metro US 6427093 USPAT 20020730 700/121 Method and apparatus for Toprac; US 6427093 ₽ 81 $\mathsf{c}\mathsf{c}\mathsf{c}\mathsf{c}$ optimal wafer-by-wafer Anthony J. US 6419801 13 USPAT | 20020716 Method and apparatus for 204/192. Smith, Jr. US 6419801 Michael Lane et 😾 🖸 🗀 🗀 C | B1 monitoring plasma 13 nmession operations.... Method and apparatus for US 6383402 USPAT |20020507 216/60 Smith, Jr. US 6383402 Michael Lane et 祭 ロ ロ ロ ∏ B1 monitoring plasma Smith, Jr.; aracessina aneration US 6275740 Method and apparatus for USPAT 20010814 700/108 US 6275740 Michael Lane et 😾 🗀 🖸 🗀 C BI monitoring plasma orocession operatio Smith, Jr.; US 6269278 16 USPAT 20010731 Method and apparatus for 700/121 Michael Lane et 🗗 🗀 🗀 C | B1 ٣ monitoring plasma nrocessing operations.... Method and apparatus for Smith, Jr. US 6261470 17 USPAT 20010717 216/60 Michael Lane et 🗭 🗀 🗀 П В1 monitoring plasma nrocession operations.... Method and apparatus for Smith, Jr.: US 6254717 18 USPAT 20010703 158/345. US 8254717 Michael Lane et 🗭 🗀 🗀 🗀 □ В1 monitoring plasma nrocession operations Method and apparatus for US 6246473 19 USPAT 20010612 356/316 Smith, Jr.; US 6246473 Michael Lane et 🗷 🗀 🖸 🖸 F 81 monitoring plasma nrocessing operations Method and apparatus for al. Smith, Jr.; US 6223755 20 USPAT 20010501 134/1.1 US 6223755 Michael Lane et 🗷 🗆 🗆 🗆 ∏ B1 monitoring plasma nrocession onerations.... Method and apparatus for US 6221679 21 USPAT 20010424 438/7 US 6221679 Michael Lane et 🗭 🗀 🗀 ∏ B1 monitoring plasma nrocessing operations.... Method and apparatus for al......Smith, Jr.; US 6192826 22 USPAT 20010227 118/723 US 6192826 Michael Lane et 🕏 🗀 🗀 🗀 ∏ B1 monitoring plasma AN nrncessing operations.... Method and apparatus for al..... Smith, Jr.: 23 US 6169933 USPAT 20010102 700/121 US 6169933 Michael Lane et 🕫 🗀 🗀 🗀 monitoring plasma nrocession operations.... Method and apparatus for al..... Smith, Jr.: 24 US 6165312 A USPAT | 20001226 156/345. US 6165312 Michael Lane et 🗗 🗀 🗀 ୮ monitoring plasma 24 orncessing operations.... Method and apparatus for al..... Smith. Jr.: 25 US 6157447 A USPAT 20001205 358/316 US 6157447 Michael Lane et 💆 🏳 🏳 🖺 monitoring plasma rncessina anerations Smith. Jr.: 26 US 8134005 A USPAT | 20001017 Method and apparatus for 358/451 US 8134005 Michael Lane et P F F monitoring plasma 204/298. Smith, Jr.; rocessina anerations 77 US 6132577 A USPAT 20001017 Method and apparatus for US 6132577 Michael Lane et 🗸 ୮ ୮ ୮ monitoring plasma 32 orocessing operations Smith. Jr.: US 6123983 A USPAT 20000926 28 427/10 Method and apparatus for US 6123983 Michael Lane et 🗸 ୮ ୮ ୮ monitoring plasma arncessing operations 29 US 6090302 A USPAT 20000718 216/60 Smith Jr.: Method and apparatus for US 6090302 Michael Lane et 🗸 🏳 🗀 🗀 monitoring plasma rocessing operations US 6077386 A USPAT 20000620 30 Method and apparatus for 156/345. Smith, Jr.; US 6077386 Michael Lane et ア に 「 に monitoring plasma 24 vocessing operation US 6041270 A USPAT 20000321 31 700/121 Steffan; Paul J. Automatic recipe adjust and US 6041270 rnnn download based on process et al. ontrol window 32 US 5926690 A USPAT 19990720 Run-to-run control process 438/17 Toprac: Anthony John et 🗆 🗀 🗀 🗀 for controlling critical al Zou; Jianping et ₹ □ □ 33 US 6748280 Semiconductor run-to-run USPAT 20040608 700/31 C 81 control system with state and indel navameter estimation 34 US 8825513 700/121 USPAT | 20030923 Run-to-run control over Lymberopoulos US 6825513 ₽ B1 cccc semiconductor processing Dimitris et al. nol, based, unon, mirror, imag US 6738682 35 USPAT 20040518 700/100 Method and apparatus for Pasadyn; US 6738682 P B1 cccc scheduling based on state Alexander J. estimation uncertainties US 6735493 38 USPAT 20040511 700/121 Chou; Alton et Recipe management system US 6735493 ₽ B1 olololo al. US 6733618 37 USPAT 20040511 Disturbance-free Kagoshima; 156/345 US 6733618 RCCC recipe-controlled plasma 24 Akira et al. nonessino.system.and.meth Multi-tool control system, US 6640151 30 USPAT 20031028 Somekh; 700/121 US 6640151 P 81 cccc method and medium Sasson et al 🗸 Hills 🤭 Detells 🐯 HTML

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